

Photocouplers GaAlAs Infrared LED & Photo IC

# TLP2662,TLP2662F

#### 1. Applications

- Factory Automation (FA)
- · High-Speed Digital Interfacing for Instrumentation and Control Devices
- · Measuring Instruments

#### 2. General

The TLP2662/TLP2662F consists of high-intensity GaAlAs infrared light-emitting diodes (LEDs) optically coupled to a high-gain, high-speed photoreceptor chip. The TLP2662/TLP2662F guarantees operation at up to 125 °C and on supplies from 2.7 V to 5.5 V. It is offered in the DIP8 package. With two LED-photoreceptor pairs, the TLP2662/TLP2662F helps save board space. An internal noise shield provides superior common-mode rejection for improved noise immunity of  $\pm 20$  kV/ $\mu$ s.

#### 3. Features

- (1) Inverter logic type (open collector output)
- (2) Package: DIP8
- (3) Operating temperature: -40 to 125 °C
- (4) Supply voltage: 2.7 to 5.5 V
- (5) Data transfer rate: 10 MBd (typ.) (NRZ)
- (6) Threshold input current: 5.0 mA (max)
- (7) Supply current: 8 mA (max)
- (8) Common-mode transient immunity: ±20 kV/µs (min)
- (9) Isolation voltage: 5000 Vrms (min)
- (10) Safety standards

UL-approved: UL1577, File No.E67349

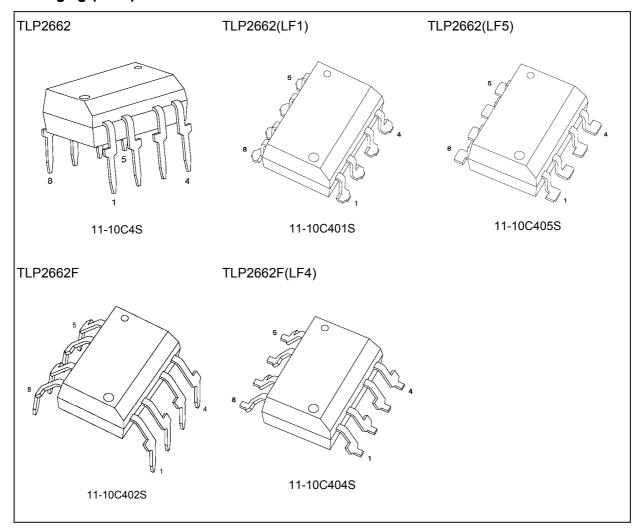
cUL-approved: CSA Component Acceptance Service No.5A File No.E67349

VDE-approved: EN60747-5-5 (Note 1)

Note 1: When an EN60747-5-5 approved type is needed, please designate the Option (D4).

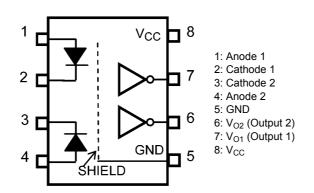


## 4. Packaging (Note)



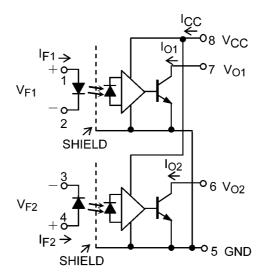
Note: Lead-formed product: (LF1), (LF4), (LF5)

#### 5. Pin Assignment





#### 6. Internal Circuit



## 7. Principle of Operation

#### 7.1. Truth Table

Input	LED	Output
Н	ON	L
L	OFF	Н

#### 7.2. Mechanical Parameters

Characteristics	7.62-mm pitch TLP2662	10.16-mm pitch TLP2662F	Unit
Creepage distances	7.0 (min)	8.0 (min)	mm
Clearance distances	7.0 (min)	8.0 (min)	mm
Internal isolation thickness	0.4 (min)	0.4 (min)	mm



## 8. Absolute Maximum Ratings (Note) (Unless otherwise specified, T<sub>a</sub> = 25 °C)

	Characteristics	Test Condition	Symbol	Note	Rating	Unit
LED	Input forward current		I <sub>F</sub>	(Note 1)	20	mA
	Input forward current derating	(T <sub>a</sub> ≥ 116 °C)	$\Delta I_F/\Delta T_a$	(Note 1)	-0.6	mA/°C
	Input forward current (pulsed)		I <sub>FP</sub>	(Note 1), (Note 2)	40	mA
	Input forward current derating (pulsed)	(T <sub>a</sub> ≥ 116 °C)	ΔI <sub>FP</sub> /ΔT <sub>a</sub>	(Note 1)	-1.17	mA/°C
	Peak transient input forward current		I <sub>FPT</sub>	(Note 1), (Note 3)	1	A
	Peak transient input forward current derating	(T <sub>a</sub> ≥ 116 °C)	$\Delta I_{FPT}/\Delta T_a$	(Note 1)	-29.4	mA/°C
	Input power dissipation		$P_{D}$	(Note 1)	40	mW
	Input power dissipation derating	(T <sub>a</sub> ≥ 116 °C)	$\Delta P_D/\Delta T_a$	(Note 1)	-1.17	mW/°C
	Input reverse voltage		$V_R$	(Note 1)	5	V
Detector	Output current		I <sub>O</sub>	(Note 1)	25	mA
	Output voltage		Vo	(Note 1)	6	V
	Supply voltage		V <sub>CC</sub>		6	V
	Output power dissipation		Po	(Note 1)	85	mW
	Output power dissipation derating	$(T_a \ge 110  ^{\circ}\text{C})$	$\Delta P_0/\Delta T_a$	(Note 1)	-2.1	mW/°C
Common	Operating temperature		T <sub>opr</sub>		-40 to 125	°C
	Storage temperature		T <sub>stg</sub>		-55 to 150	°C
	Lead soldering temperature	(10 s)	T <sub>sol</sub>		260	°C
	Isolation voltage	AC, 60 s., R.H. ≤ 60 %	BV <sub>S</sub>	(Note 4)	5000	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Each channel

Note 2: Pulse width (PW)  $\leq$  1 ms, duty = 50 %

Note 3: Pulse width (PW)  $\leq$  1  $\mu$ s, duty = 300 pps

Note 4: This device is considered as a two-terminal device: Pins 1, 2, 3 and 4 are shorted together, and pins 5, 6, 7 and 8 are shorted together.

## 9. Recommended Operating Conditions (Note)

Characteristics	Symbol	Note	Min	Тур.	Max	Unit
Input on-state current	I <sub>F(ON)</sub>	(Note 1), (Note 2)	6	_	15	mA
Input off-state voltage	V <sub>F(OFF)</sub>	(Note 1)	0	_	0.8	V
Supply voltage	V <sub>CC</sub>	(Note 3)	2.7	3.3/5.0	5.5	V
Operating temperature	T <sub>opr</sub>		-40	_	125	°C

Note: The recommended operating conditions are given as a design guide necessary to obtain the intended performance of the device. Each parameter is an independent value. When creating a system design using this device, the electrical characteristics specified in this datasheet should also be considered.

Note: A ceramic capacitor  $(0.1~\mu F)$  should be connected between pin 8 and pin 5 to stabilize the operation of a high-gain linear amplifier. Otherwise, this photocoupler may not switch properly. The bypass capacitor should be placed within 1 cm of each pin.

Note 1: Each channel

Note 2: The rise and fall times of the input on-current should be less than 0.5  $\mu$ s.

Note 3: Denotes the operating range, not the recommended operating condition.



# 10. Electrical Characteristics (Note) (Unless otherwise specified, $T_a$ = -40 to 125 °C, $V_{CC}$ = 2.7 to 5.5 V)

Characteristics	Symbol	Note	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Input forward voltage	V <sub>F</sub>	(Note 1)		I <sub>F</sub> = 10 mA, T <sub>a</sub> = 25 °C	1.45	1.55	1.7	V
Input forward voltage temperature coefficient	$\Delta V_F/\Delta T_a$	(Note 1)		I <sub>F</sub> = 10 mA	_	-2.0	ı	mV/°C
Input reverse current	I <sub>R</sub>	(Note 1)		V <sub>R</sub> = 5 V, T <sub>a</sub> = 25 °C	_		10	μА
Input capacitance	Ct	(Note 1)		V = 0 V, f = 1 MHz, T <sub>a</sub> = 25 °C	_	60	_	pF
High-level output current	Іон	(Note 1)	Fig. 13.1.1	$V_F = 0.8 \text{ V}, V_O = 5.5 \text{ V}, V_{CC} = 5.5 \text{ V}$	_	l	50	μΑ
			Fig. 13.1.1	$V_F = 0.8 \text{ V}, V_O = 5.5 \text{ V}, V_{CC} = 5.5 \text{ V}, T_a = 25 ^{\circ}\text{C}$	_		10	μА
Low-level output voltage	V <sub>OL</sub>	(Note 1)	Fig. 13.1.2	$I_F = 10 \text{ mA},$ $I_O = 13 \text{ mA} \text{ (Sinking)}$	_	0.2	0.6	V
Low-level supply current	I <sub>CCL</sub>		Fig. 13.1.4	I <sub>F1</sub> =I <sub>F2</sub> = 10 mA	_	3.8	8	mA
High-level supply current	Іссн		Fig. 13.1.3	I <sub>F1</sub> =I <sub>F2</sub> = 0 mA	_	3.4	8	mA
Threshold input current (H/L)	I <sub>FHL</sub>	(Note 1)		I <sub>O</sub> = 13 mA (Sinking), V <sub>O</sub> < 0.6 V, T <sub>a</sub> = 25 °C	_	1.3	2.8	mA
				$I_O$ = 13 mA (Sinking), $V_O$ < 0.6 V	_		5.0	mA

Note: All typical values are at  $T_a = 25$  °C.

Note 1: Each channel

## 11. Isolation Characteristics (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics	Symbol	Note	Test Condition	Min	Тур.	Max	Unit
Total capacitance (input to output)	Cs	(Note 1)	V <sub>S</sub> = 0 V, f = 1 MHz		1.0		pF
Isolation resistance	R <sub>S</sub>	(Note 1)	V <sub>S</sub> = 500 V, R.H. ≤ 60 %	1 × 10 <sup>12</sup>	1014	_	Ω
Isolation voltage	BVS	(Note 1)	AC, 60 s	5000			Vrms
			AC, 1 s in oil		10000	_	Vrms
			DC, 60 s in oil		10000		Vdc

Note 1: This device is considered as a two-terminal device: Pins 1, 2, 3 and 4 are shorted together, and pins 5, 6, 7 and 8 are shorted together.



# 12. Switching Characteristics (Note) (Unless otherwise specified, T<sub>a</sub> = -40 to 125 °C, V<sub>CC</sub> = 2.7 to 5.5 V (Each channel))

Characteristics	Symbol	Note	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Propagation delay time (H/L)	t <sub>pHL</sub>	(Note 1)	Fig. 13.1.5	$\begin{aligned} I_F &= 0 \rightarrow 7.5 \text{ mA, } R_L = 350 \ \Omega, \\ C_L &= 15 \text{ pF} \end{aligned}$	_	27	75	ns
Propagation delay time (L/H)	t <sub>pLH</sub>	(Note 1)	Fig. 13.1.5	$I_F$ = 7.5 $\rightarrow$ 0 mA, $R_L$ = 350 $\Omega$ , $C_L$ = 15 pF		25	75	ns
Pulse width distortion	t <sub>pHL</sub> - t <sub>pLH</sub>	(Note 1)		$I_F = 0 \longleftrightarrow 7.5 \text{ mA},$ $R_L = 350 \Omega, C_L = 15 \text{ pF}$	-	_	35	ns
Propagation delay skew (device to device)	t <sub>psk</sub>	(Note 1), (Note 2)		$I_F = 0 \longleftrightarrow 7.5 \text{ mA},$ $R_L = 350 \Omega, C_L = 15 \text{ pF}$	-40	_	40	ns
Fall time	t <sub>f</sub>	(Note 1)		$I_F$ = 0 $\rightarrow$ 7.5 mA, $R_L$ = 350 $\Omega$ , $C_L$ = 15 pF	_	3	_	ns
Rise time	t <sub>r</sub>	(Note 1)	Fig. 13.1.5	$I_F$ = 7.5 $\rightarrow$ 0 mA, $R_L$ = 350 $\Omega$ , $C_L$ = 15 pF	_	12	_	ns
Common-mode transient immunity at output high	CM <sub>H</sub>		Fig. 13.1.6	$V_{CM}$ = 1000 $V_{p-p}$ , $I_F$ = 0 mA, $V_{CC}$ = 3.3 V/5 V, $T_a$ = 25 °C	±20	±25	_	kV/μs
Common-mode transient immunity at output low	CM <sub>L</sub>		Fig. 13.1.6	$V_{CM} = 1000 V_{p-p}, I_F = 10 \text{ mA},$ $V_{CC} = 3.3 \text{ V/5 V}, T_a = 25 ^{\circ}\text{C}$	±20	±25	_	kV/μs

Note: All typical values are at  $T_a = 25$  °C.

Note 1: f = 5 MHz, duty = 50 %, input current  $t_r = t_f = 5$  ns,  $C_L$  is approximately 15 pF which includes probe and stray wiring capacitance.

Note 2: The propagation delay skew,  $t_{psk}$ , is equal to the magnitude of the worst-case difference in  $t_{pHL}$  and/or  $t_{pLH}$  that will be seen between units at the same given conditions (supply voltage, input current, temperature, etc).

#### 13. Test Circuits and Characteristics Curves

#### 13.1. Test Circuits

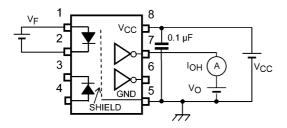


Fig. 13.1.1 I<sub>OH</sub> Test Circuit

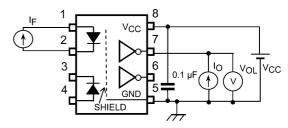


Fig. 13.1.2 V<sub>OL</sub> Test Circuit

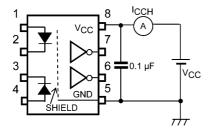


Fig. 13.1.3 I<sub>CCH</sub> Test Circuit

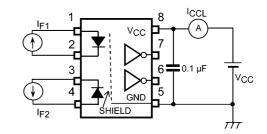


Fig. 13.1.4 I<sub>CCL</sub> Test Circuit

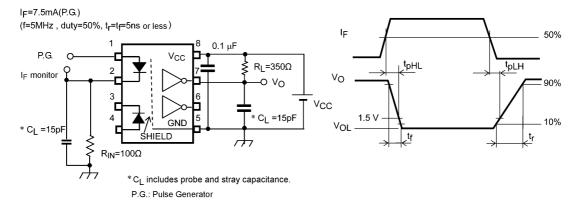


Fig. 13.1.5 Switching Time Test Circuit and Waveform

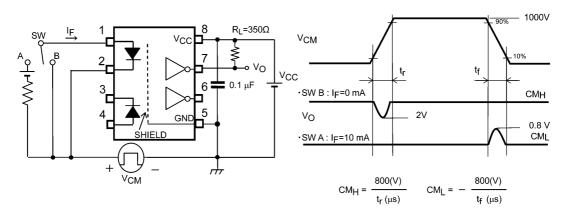
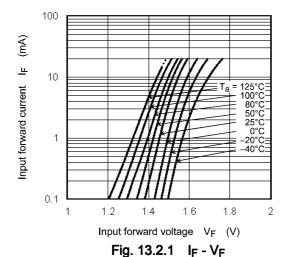


Fig. 13.1.6 Common-Mode Transient Immunity and Waveform

### 13.2. Characteristics Curves (Note)



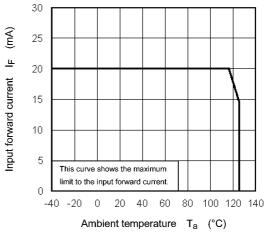


Fig. 13.2.2 I<sub>F</sub> - T<sub>a</sub>

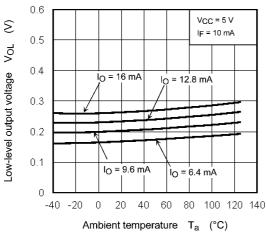


Fig. 13.2.3 V<sub>OL</sub> - T<sub>a</sub>

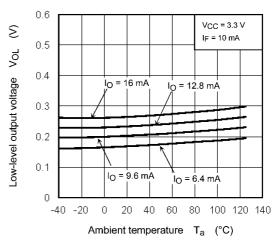
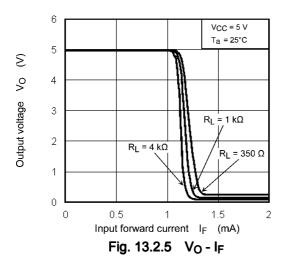


Fig. 13.2.4 V<sub>OL</sub> - T<sub>a</sub>



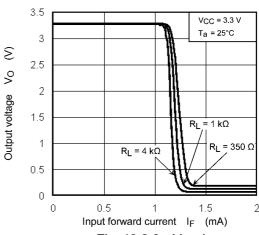
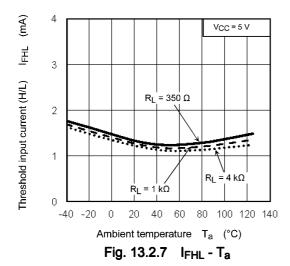


Fig. 13.2.6 V<sub>O</sub> - I<sub>F</sub>



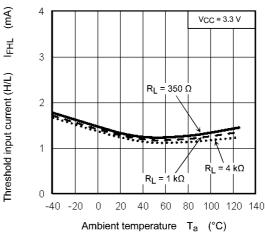
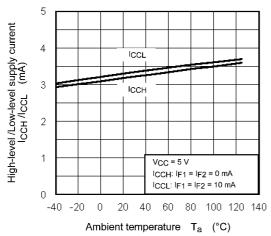


Fig. 13.2.8 I<sub>FHL</sub> - T<sub>a</sub>



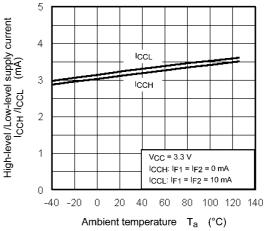
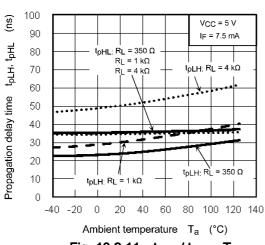


Fig. 13.2.9 | I<sub>CCH</sub> / I<sub>CCL</sub> - T<sub>a</sub>





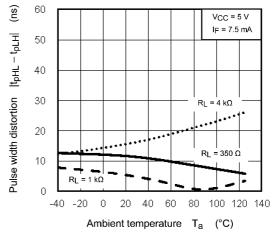
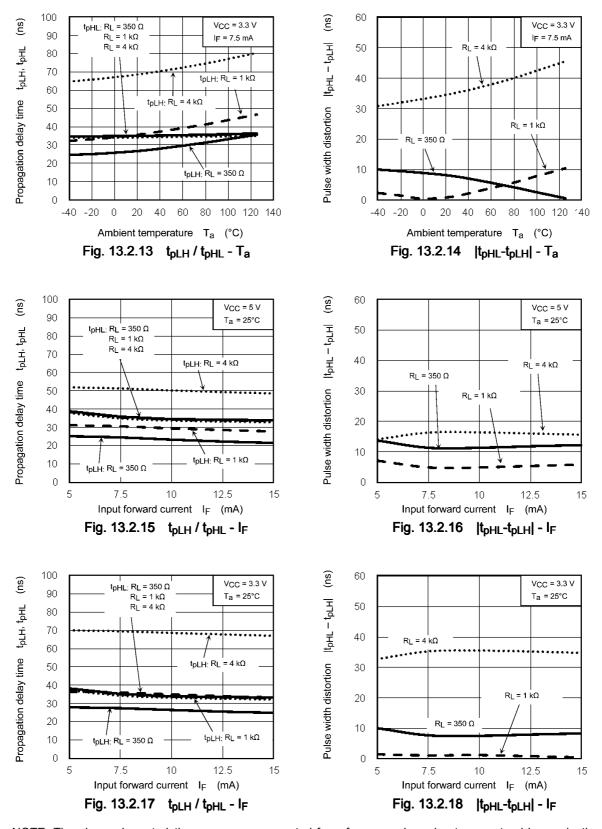


Fig. 13.2.11  $t_{pLH} / t_{pHL} - T_a$ 

Fig. 13.2.12 |t<sub>pHL</sub>-t<sub>pLH</sub>| - T<sub>a</sub>



NOTE: The above characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

#### 14. Soldering and Storage

#### 14.1. Precautions for Soldering

The soldering temperature should be controlled as closely as possible to the conditions shown below, irrespective of whether a soldering iron or a reflow soldering method is used.

When using soldering reflow.

The soldering temperature profile is based on the package surface temperature.

(See the figure shown below, which is based on the package surface temperature.)

Reflow soldering must be performed once or twice.

The mounting should be completed with the interval from the first to the last mountings being 2 weeks.

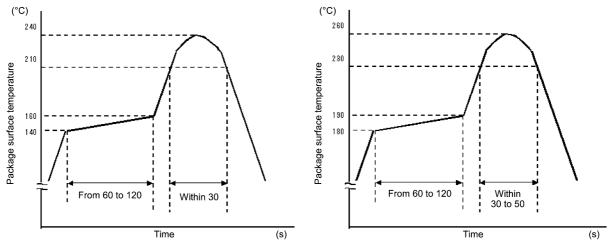


Fig. 14.1.1 An Example of a Temperature Profile Fig. 14.1.2 An Example of a Temperature Profile When Sn-Pb Eutectic Solder Is Used When Lead(Pb)-Free Solder Is Used

- When using soldering flow (Applicable to both eutectic solder and Lead(Pb)-Free solder)
   Preheat the device at a temperature of 150 °C (package surface temperature) for 60 to 120 seconds.
   Mounting condition of 260 °C within 10 seconds is recommended.
   Flow soldering must be performed once.
- · When using soldering Iron

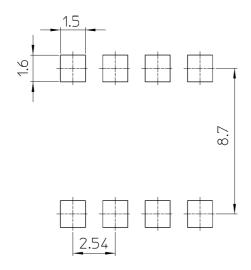
Complete soldering within 10 seconds for lead temperature not exceeding 260 °C or within 3 seconds not exceeding 350 °C

Heating by soldering iron must be done only once per lead.

#### 14.2. Precautions for General Storage

- · Avoid storage locations where devices may be exposed to moisture or direct sunlight.
- · Follow the precautions printed on the packing label of the device for transportation and storage.
- Keep the storage location temperature and humidity within a range of 5 °C to 35 °C and 45 % to 75 %, respectively.
- Do not store the products in locations with poisonous gases (especially corrosive gases) or in dusty conditions.
- Store the products in locations with minimal temperature fluctuations. Rapid temperature changes during storage can cause condensation, resulting in lead oxidation or corrosion, which will deteriorate the solderability of the leads.
- · When restoring devices after removal from their packing, use anti-static containers.
- Do not allow loads to be applied directly to devices while they are in storage.
- If devices have been stored for more than two years under normal storage conditions, it is recommended that you check the leads for ease of soldering prior to use.

## 15. Land Pattern Dimensions (for reference only)





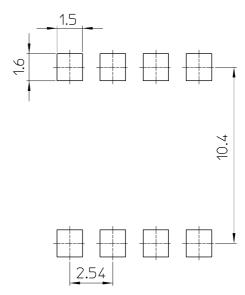
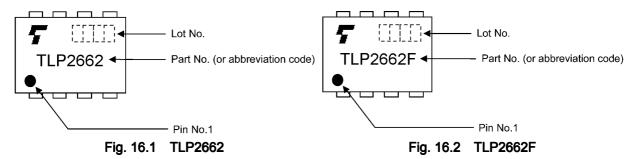


Fig. 15.2 (LF4) Type (Unit: mm)

### 16. Marking





## 17. EN60747-5-5 Option (D4) Specification

• Part number: TLP2662 (Note 1)

• The following part naming conventions are used for the devices that have been qualified according to option (D4) of EN60747.

Example: TLP2662(D4-TP1,F)

D4: EN60747 option TP1: Tape type

F: [[G]]/RoHS COMPATIBLE (Note 2)

Note 1: Use TOSHIBA standard type number for safety standard application.

e.g., TLP2662(D4-TP1,F)  $\rightarrow$  TLP2662

Note 2: Please contact your Toshiba sales representative for details on environmental information such as the product's RoHS compatibility.

RoHS is the Directive 2011/65/EU of the European Parliament and of the Council of 8 June 2011 on the restriction of the use of certain hazardous substances in electrical and electronics equipment.

Description	Symbol	Rating	Unit	
Application classification  for rated mains voltage ≤ 300 Vrms for rated mains voltage ≤ 600 Vrms		I-IV I-III	_	
Climatic classification			40 / 125 / 21	_
Pollution degree			2	_
Manda and the state of the stat	TLPxxx type	.,	890	) (n 1
Maximum operating insulation voltage	TLPxxxF type	VIORM	1140	Vpeak
Input to output test voltage, Method A	TLPxxx type	V <sub>pr</sub>	1424	· Vpeak
$V_{pr}$ = 1.6 × $V_{IORM}$ , type and sample test $t_p$ = 10 s, partial discharge < 5 pC	TLPxxxF type		1824	
Input to output test voltage, Method B	TLPxxx type	V <sub>pr</sub>	1670	Vpeak
$V_{pr}$ = 1.875 × $V_{IORM}$ , 100 % production test $t_p$ = 1 s, partial discharge < 5 pC	TLPxxxF type		2140	
Highest permissible overvoltage (transient overvoltage, t <sub>pr</sub> = 60 s)		V <sub>TR</sub>	8000	Vpeak
Safety limiting values (max. permissible ratings in case of also refer to thermal derating out current (input current I <sub>F</sub> , P <sub>so</sub> = 0) power (output or total power dissipation) temperature		I <sub>si</sub> P <sub>so</sub> T <sub>s</sub>	100 800 150	mA mW °C
Insulation resistance $V_{IO}$ = 500 V, $T_a$ = 25 °C $V_{IO}$ = 500 V, $T_a$ = 100 °C $V_{IO}$ = 500 V, $T_a$ = $T_s$	;	R <sub>si</sub>		Ω

Fig. 17.1 EN60747 Isolation Characteristics

		7.62 mm pitch	10.16 mm pitch TLPxxxF type	
Minimum arganga distance	C tr	TLPxxx type		
Minimum creepage distance	Cr	7.0 mm	8.0 mm	
Minimum clearance	CI	7.0 mm	8.0 mm	
Minimum insulation thickness	ti	0.4 mm		
Comparative tracking index	СТІ	175		

Fig. 17.2 Insulation Related Specifications (Note)

Note: If a printed circuit is incorporated, the creepage distance and clearance may be reduced below this value. (e. g., at a standard distance between soldering eye centers of 7.5 mm). If this is not permissible, the user shall take suitable measures.

Note: This photocoupler is suitable for **safe electrical isolation** only within the safety limit data. Maintenance of the safety data shall be ensured by means of protective circuits.

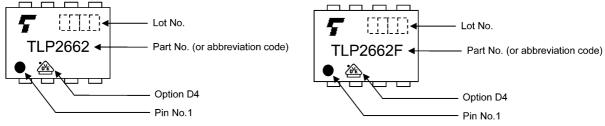
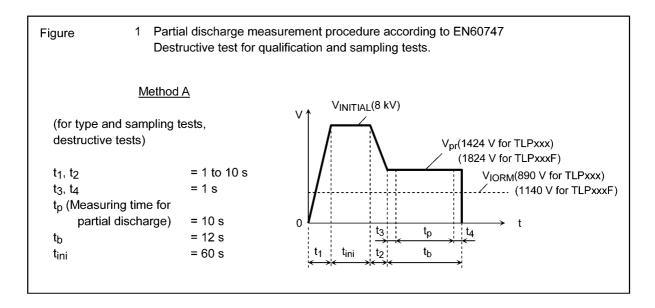
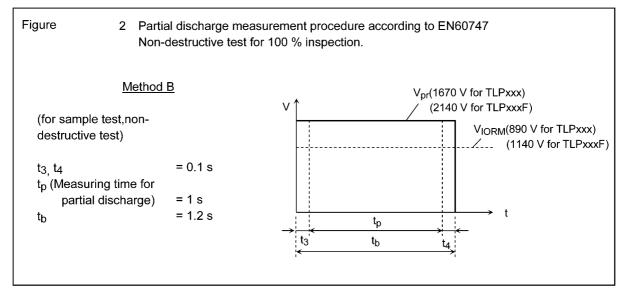


Fig. 17.3 TLP2662 Marking Example

Fig. 17.4 TLP2662F Marking Example

Note: The above marking is applied to the photocouplers that have been qualified according to option (D4) of EN60747.





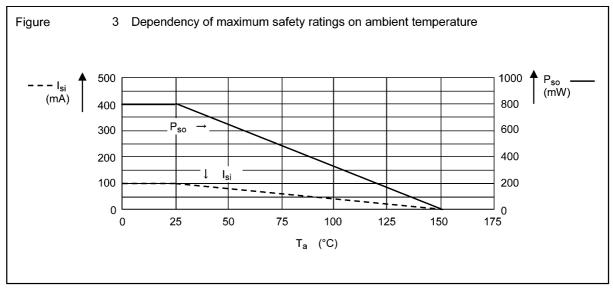
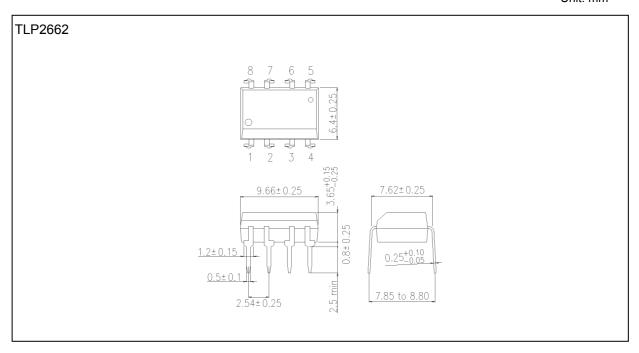


Fig. 17.5 Measurement Procedure



## **Package Dimensions**

Unit: mm

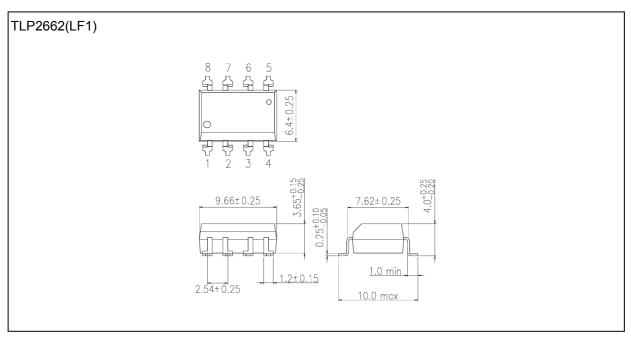


Weight: 0.54 g (typ.)

	Package Name(s)
TOSHIBA: 11-10C4S	

## **Package Dimensions**

Unit: mm



Weight: 0.53 g (typ.)

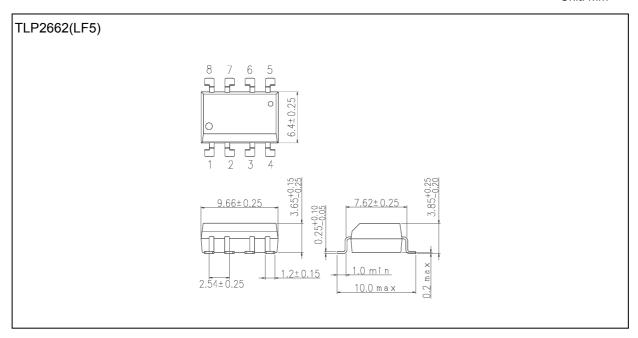
Package Name(s)
TOSHIBA: 11-10C401S

Rev.5.0

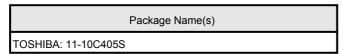


## **Package Dimensions**

Unit: mm

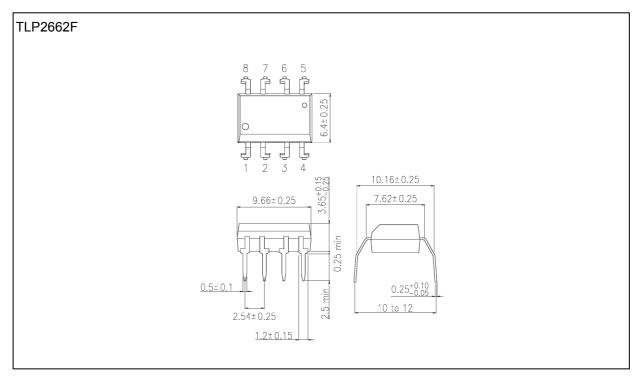


Weight: 0.53 g (typ.)



#### **Package Dimensions**

Unit: mm



Weight: 0.54 g (typ.)

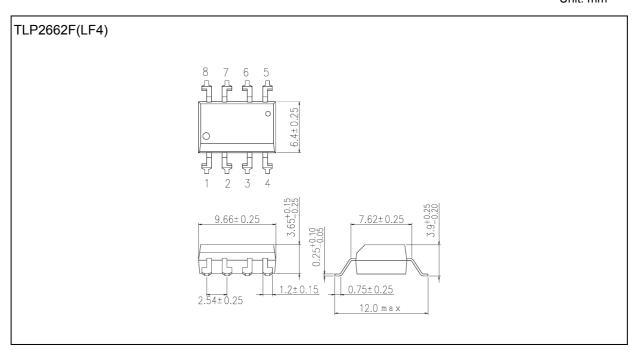
	Package Name(s)
TOSHIBA: 11-10C402S	

Rev.5.0



## **Package Dimensions**

Unit: mm



Weight: 0.53 g (typ.)

Package Name(s)	
TOSHIBA: 11-10C404S	



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